

Call for papers

Measurement Science and Technology

Special Issue on Imaging Systems and Techniques



After the 2015 IEEE International Conference on Imaging Systems and Techniques, Measurement Science and Technology published a Special Issue, which you can read on the web link: <http://iopscience.iop.org/issue/0957-0233/27/11>

This is a call for papers for a Special Issue on Imaging Systems and Techniques, which will be published by the Measurement Science and Technology journal. If you would like to submit a revised version of your paper which has been presented at the 2016 IEEE International Conference on Imaging Systems and Techniques, please take this opportunity to **substantially** expand your paper (at least 50%) to reach the journal standard, as otherwise your paper may be rejected. The journal editor said that last year several papers submitted to the special issue were rejected straight away because they were too similar to the conference papers. All submissions will be reviewed following the journal's normal procedure.

Paper format and submission

For general author guidelines, formatting information, scope and length limits, you can read <http://iopscience.iop.org/0957-0233/page/Scope>. To submit a paper, please go to <https://mc04.manuscriptcentral.com/mst-iop>, and follow the procedure below.

- If this is the first time you submit a paper to this journal, you need to register on the above web page.
- After you log in, select Author/Start New Submission, and then click Begin Submission
- Select Special Issue Article
- Select Special Issue on Imaging Systems and Techniques 2016
- Please also provide the ID Number of your conference paper.

Schedule

- Deadline for manuscript submission: 15 Dec. 2016
- Planned publication date: 2nd Quarter 2016

Guest editors

Wuqiang Yang, University of Manchester, UK, w.yang@manchester.ac.uk
Michalis Zervakis, Technical University of Crete, Greece, michalis@display.tuc.gr
Lijun Xu, Beihang University, China, lijunxu@buaa.edu.cn
George Giakos, Manhattan College, USA, george.giakos@manhattan.edu